Supplementary material

	J _{sc} [mA/cm ²]	V _{oc} [mV]	FF [%]	PCE [%]
PTB7:PC ₇₁ BM devices	17.68	729.98	56.04	7.23
P3HT:PC ₇₁ BM devices	9.83	618.60	45.33	2.80

Table S1: Photovoltaic parameters of PTB7:PC71BM and P3HT:PC71BM devices.



FIG. S1. (a) J-V characteristics curves and (b) EQE curves for PTB7:PC₇₁BM and P3HT:PC₇₁BM fresh devices.



FIG. S2. A comparison of absorbance of fresh P3HT:PCB₇₁M film measured using R&T and PDS techniques is shown in the figure above. Whilst the measured absorbance from R&T method drops off very quickly beyond 650nm due to its low sensitivity, the detailed sub-bandgap features are observed using PDS, which is 2 orders of magnitude more sensitive than the R&T method.

Urbach energy calculation:



FIG. S3. Calculation of Urbach energy of fresh PTB7:PC₇₁BM film from the slope of the linear region of normalized PDS signal is shown in the figure above. The Urbach energy of PTB7:PC₇₁BM and P3HT:PC₇₁BM (both fresh and aged) is summarized in the following table:

Film Description	Urbach Energy (meV)
Fresh P3HT:PC71BM	109.9
Aged P3HT:PC ₇₁ BM	109.8
Fresh PTB7:PC71BM	48.9
Aged PTB7:PC ₇₁ BM	71.1

Sub-bandgap absorption co-efficient (α cm⁻¹) in region-3:

The area under the PDS curve in region 3, $\int \alpha dE$, is directly related to the density of defect states [1]. To calculate this area, we first need to isolate the absorption in region 3, and fit this region with a Gaussian function. For example, the Gaussian expression used to fit the PTB7:PC₇₁BM fresh film is as follows:

$$y = y_0 + \frac{A}{w \times \sqrt{\frac{\pi}{4 \times ln^{[ro]}(2)}}} \times e^{\frac{-4 \times ln^{[ro]}(2) \times (x - x_c)^2}{w^2}}$$

The Gaussian fits for all four samples are shown in Fig. S5.



FIG. S4. Gaussian fits of absorption coefficient in region 3 (low energy region).

These functions were then integrated over the displayed energy range. From this, we can compare the area under the curve for fresh and aged films, as shown below. The ratio for PTB7 is considerably higher.

Film	Ratio of area under sub-bandgap absorption curve of aged and fresh films, ∫α.dE
P3HT:PC ₇₁ BM	1.14
PTB7:PC71BM	2.60

REF:

[1] W.B. Jackson, N.M. Amer, Direct measurement of gap-state absorption in hydrogenated amorphous silicon by photothermal deflection spectroscopy, Physical Review B, 25 (1982) 5559-5562.



FIG. S5. Hourly absorption spectra of (a) P3HT:PC₇₁BM and (b) PTB7:PC₇₁BM films under continuous 1-sun illumination. All spectra was normalised to the absorption at 370 nm.



FIG. S6. Hourly PL spectra of (a) P3HT:PC₇₁BM and (b) PTB7:PC₇₁BM films under continuous 1-sun illumination.



FIG. S7. AFM images (5 μ m x 5 μ m) of P3HT:PC₇₁BM and PTB7:PC₇₁BM films under both fresh and aged conditions. The RMS surface roughness extracted from AFM images are summarized in the following table:

Film Description	RMS Surface Roughness (in nm) from AFM
Fresh P3HT:PC71BM	2.27
Aged P3HT:PC71BM	2.24
Fresh PTB7:PC71BM	2.74
Aged PTB7:PC ₇₁ BM	2.27



FIG. S8. X-ray diffraction patterns of P3HT:PC₇₁BM and PTB7:PC₇₁BM films under both fresh and aged conditions



FIG. S9. Chemical structures of the repeat unit consisting BDT and TT for the polymer donor PTB7